

<b>Issue Classification</b>		Application/Control No.	Applicant(s)/Patent under Reexamination
		09/925,247	AWAD ET AL.
		Examiner	Art Unit
		Jia W. Lu	2634

<b>ISSUE CLASSIFICATION</b>			
<b>ORIGINAL</b>		<b>CROSS-REFERENCE(S)</b>	
<b>CLASS</b>	<b>SUBCLASS</b>	<b>CLASS</b>	<b>SUBCLASS (ONE SUBCLASS PER BLOCK)</b>
375	232	375	346
<b>INTERNATIONAL CLASSIFICATION</b>			
1	0	3	1
			7/30
			/
			/
			/
			/
<b>Jia Lu</b> 4/20/05 (Assistant Examiner) (Date)		<b>STEPHEN CHIN</b> 2634 <b>Supervisory Patent Examiner</b> <b>Technology Center 2600</b> (Primary Examiner) (Date)	
<b>Lashawn Marks</b> 4/20/05 (Legal Instruments Examiner) (Date)		<b>O.G.</b> Print Claim(s) <input type="checkbox"/> <b>O.G.</b> Print Fig. <input type="checkbox"/>	

<input type="checkbox"/> Claims renumbered in the same order as presented by applicant		<input type="checkbox"/> CPA		<input type="checkbox"/> T.D.		<input type="checkbox"/> R.1.47	
Final	Original	Final	Original	Final	Original	Final	Original
1	1	31	61	91	121	151	181
2	2	32	62	92	122	152	182
3	3	33	63	93	123	153	183
4	34	64	94	124	125	154	184
5	35	65	95	126	127	155	185
6	36	66	96	128	129	156	186
7	37	67	97	130	131	157	187
8	38	68	98	132	133	158	188
9	39	69	99	134	135	159	189
10	40	70	100	136	137	160	190
11	41	71	101	138	139	161	191
12	42	72	102	140	141	162	192
13	43	73	103	142	143	163	193
14	44	74	104	144	145	164	194
15	45	75	105	146	147	165	195
16	46	76	106	148	149	166	196
17	47	77	107	150	151	167	197
18	48	78	108	152	153	168	198
19	49	79	109	154	155	169	199
20	50	80	110	156	157	170	200
21	51	81	111	158	159	171	201
22	52	82	112	160	161	172	202
23	53	83	113	162	163	173	203
24	54	84	114	164	165	174	204
25	55	85	115	166	167	175	205
26	56	86	116	168	169	176	206
27	57	87	117	170	171	177	207
28	58	88	118	172	173	178	208
29	59	89	119	174	175	179	209
30	30	60	90	120	150	180	210